

IGBT³ Chip

FEATURES:

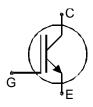
- 600V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

- power module
- discrete components

Applications:

- drives
- white goods
- resonant applications



| Chip Type | V _{CE} | I _{Cn} | Die Size | Package | Ordering Code |
|------------|-----------------|-----------------|-----------------------------|--------------|-----------------------|
| SIGC08T60S | 600V | 15A | 2.86 x 2.82 mm ² | sawn on foil | Q67050- A4395-A101 |

MECHANICAL PARAMETER:

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|---------------------------------|---|-----------------|--|--|--|
| Raster size | 2.86 x 2.82 | | | | |
| Emitter pad size | 2.014 x 2.014 | mm ² | | | |
| Gate pad size | 0.361 x 0.513 | | | | |
| Area total / active | 8.0 / 5.2 | | | | |
| Thickness | 70 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 0 | deg | | | |
| Max. possible chips per wafer | 1836 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Emitter metallization | tion 3200 nm AlSiCu | | | | |
| Collector metallization | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond AI, <500µm | | | | | |
| Reject ink dot size | Ø 0.65mm ; max 1.2mm | | | | |
| Recommended storage environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



MAXIMUM RATINGS:

| Parameter | Symbol | Value | Unit | |
|--|---------------------------|----------|------|--|
| Collector-emitter voltage, Tj=25 °C | V _{CE} | 600 | V | |
| DC collector current, limited by T _{jmax} | I _C | 1) | А | |
| Pulsed collector current, t_p limited by T_{jmax} | <i>I</i> _{cpuls} | 45 | А | |
| Gate emitter voltage | V _{GE} | ±20 | V | |
| Operating junction and storage temperature | T_{j} , T_{stg} | -40 +175 | °C | |
| SC data, $V_{GE} = 15V$, $V_{CC} = 360V$, $Tvj = 150$ °C | <i>t</i> p | 5 | μs | |

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------|---|-------|------|------|------|
| | | | min. | typ. | max. | |
| Collector-emitter breakdown voltage | V _{(BR)CES} | V_{GE} =0V , I _C = 2mA | 600 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | V _{GE} =15V, I _C =15A | | 1.5 | 2.05 | V |
| Gate-emitter threshold voltage | V _{GE(th)} | I_C =210 μ A , V_{GE} = V_{CE} | 4.1 | 4.9 | 5.7 | |
| Zero gate voltage collector current | I _{CES} | V_{CE} =600V , V_{GE} =0V | | | 0.85 | μA |
| Gate-emitter leakage current | I _{GES} | $V_{CE}=0V$, $V_{GE}=20V$ | | | 300 | nA |
| Integrated gate resistor | R _{Gint} | | | none | | Ω |

ELECTRICAL CHARACTERISTICS (verified by design/characterization):

| Parameter | Symbol | Conditions | Value | | | Unit |
|------------------------------|------------------|-----------------------|-------|------|------|------|
| Falameter | Symbol | Conditions | min. | typ. | max. | |
| Input capacitance | C _{iss} | V _{CE} =25V, | | 860 | | pF |
| Output capacitance | Coss | $V_{\rm GE}=0V$, | | 55 | | |
| Reverse transfer capacitance | Crss | f=1MHz | | 24 | | |

SWITCHING CHARACTERISTICS (verified by design/characterization), inductive load

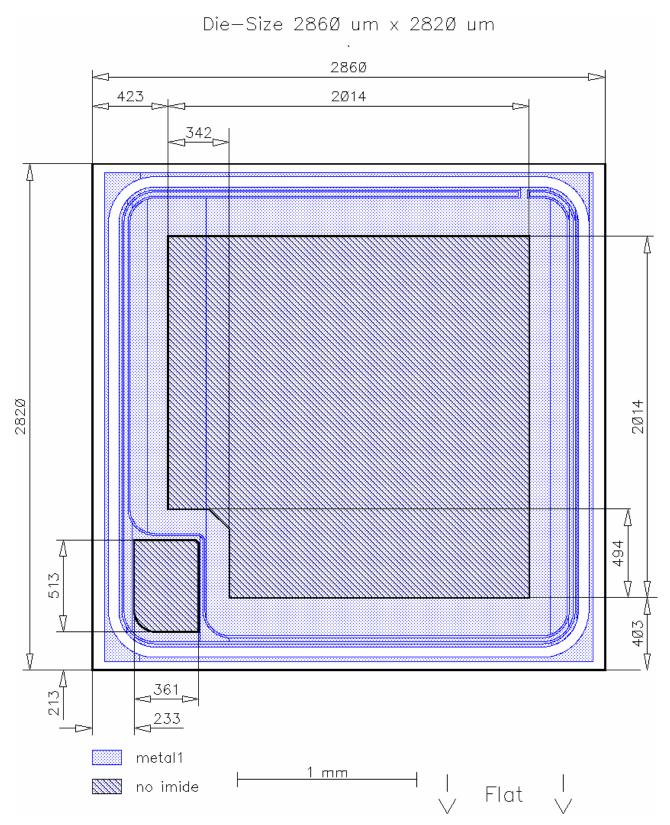
| Parameter | Symbol | Conditions | Value ²⁾ | | | Unit |
|---------------------|--------------------|---|---------------------|------|------|------|
| Falameter | | | min. | typ. | max. | |
| Turn-on delay time | t _{d(on)} | $T_j = 175 ^{\circ}\mathrm{C}$ | | 17 | | ns |
| Rise time | t _r | $V_{\rm CC} = 400 V$, | | 15 | | |
| Turn-off delay time | $t_{d(off)}$ | / _C =15A, / _{GE} =0/15V, | | 212 | | |
| Fall time | t _f | $R_{\rm G}$ = 15 Ω | | 79 | | |

²⁾ values also influenced by parasitic L- and C- in measurement and package.

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CHIP DRAWING:



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FURTHER ELECTRICAL CHARACTERISTICS:

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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